Searci	h N	lotes	(COI	ntinued)

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/827,431	TANAKA, KOICHIRO	
Examiner	Art Unit	
James Phan	2872	

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Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED				
Class	Class Subclass Date		Examine	
See Gean	ch Notes"	10/07	J.F.	

(INCLUDING SEARCH	DATE	EXMR
EAST fee attachment	4/07	11.
EAST. See attach ment	10/07	V-P
		